

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Louis N. Koppel et al.

Application No.: NEW

Filed: HEREWITH

For: CALIBRATION AND ALIGNMENT
OF X-RAY REFLECTOMETRIC
SYSTEMS

Group Art Unit: 0

Examiner: Unknown

PRELIMINARY AMENDMENT121 Spear Street, Suite 290
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M/S PATENT APPLICATION
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Prior to examining the above-identified divisional application, please amend the application as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendment to the Claims are reflected in the listing of claims which begins on page 3 of this paper.

Remarks begin on page 6 of this paper.